



## AOU460 N-Channel Enhancement Mode Field Effect Transistor

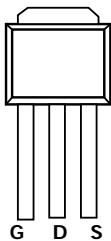
### General Description

The AOU460 uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge. This device is suitable for use in PWM, load switching and general purpose applications. Standard Product AOU460 is Pb-free (meets ROHS & Sony 259 specifications). AOU460L is a Green Product ordering option. AOU460 and AOU460L are electrically identical.

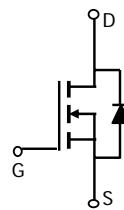
### Features

$V_{DS} (V) = 25V$   
 $I_D = 25 A \quad (V_{GS} = 10V)$   
 $R_{DS(ON)} < 14 m\Omega \quad (V_{GS} = 10V)$   
 $R_{DS(ON)} < 24 m\Omega \quad (V_{GS} = 4.5V)$

TO-251



Top View  
Drain Connected  
to Tab



### Absolute Maximum Ratings $T_A=25^\circ C$ unless otherwise noted

Parameter	Symbol	Maximum	Units
Drain-Source Voltage	$V_{DS}$	25	V
Gate-Source Voltage	$V_{GS}$	$\pm 20$	V
Continuous Drain Current <sup>G</sup>	$I_D$	25	A
$T_C=100^\circ C$		25	
Pulsed Drain Current <sup>C</sup>	$I_{DM}$	70	
Avalanche Current <sup>C</sup>	$I_{AR}$	20	A
Repetitive avalanche energy 0.1mH <sup>C</sup>	$E_{AR}$	20	mJ
Power Dissipation <sup>B</sup>	$P_D$	30	W
$T_C=25^\circ C$		15	
Junction and Storage Temperature Range	$T_J, T_{STG}$	-55 to 175	°C

### Thermal Characteristics

Parameter	Symbol	Typ	Max	Units
Maximum Junction-to-Ambient <sup>A</sup>	Steady-State	$R_{\theta JA}$	41	°C/W
Maximum Junction-to-Case <sup>B</sup>	Steady-State	$R_{\theta JC}$	3.6	5 °C/W

**Electrical Characteristics ( $T_J=25^\circ\text{C}$  unless otherwise noted)**

Symbol	Parameter	Conditions	Min	Typ	Max	Units
<b>STATIC PARAMETERS</b>						
$\text{BV}_{\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D=250\mu\text{A}, V_{GS}=0\text{V}$	25			V
$I_{DSS}$	Zero Gate Voltage Drain Current	$V_{DS}=20\text{V}, V_{GS}=0\text{V}$ $T_J=55^\circ\text{C}$	0.01	1	5	$\mu\text{A}$
$I_{GSS}$	Gate-Body leakage current	$V_{DS}=0\text{V}, V_{GS}=\pm20\text{V}$			100	nA
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$	1	1.8	2.5	V
$I_{D(\text{ON})}$	On state drain current	$V_{GS}=10\text{V}, V_{DS}=5\text{V}$	70			A
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance	$V_{GS}=10\text{V}, I_D=20\text{A}$		12	14	$\text{m}\Omega$
			$T_J=125^\circ\text{C}$		17.7	
		$V_{GS}=4.5\text{V}, I_D=20\text{A}$		20	24	
$g_{FS}$	Forward Transconductance	$V_{DS}=5\text{V}, I_D=20\text{A}$		18.9		S
$V_{SD}$	Diode Forward Voltage	$I_S=1\text{A}, V_{GS}=0\text{V}$		0.74	1	V
$I_S$	Maximum Body-Diode Continuous Current				25	A
<b>DYNAMIC PARAMETERS</b>						
$C_{iss}$	Input Capacitance	$V_{GS}=0\text{V}, V_{DS}=12.5\text{V}, f=1\text{MHz}$		830	1000	pF
$C_{oss}$	Output Capacitance			224		pF
$C_{rss}$	Reverse Transfer Capacitance			127		pF
$R_g$	Gate resistance	$V_{GS}=0\text{V}, V_{DS}=0\text{V}, f=1\text{MHz}$		0.93	1.5	$\Omega$
<b>SWITCHING PARAMETERS</b>						
$Q_g(10\text{V})$	Total Gate Charge	$V_{GS}=10\text{V}, V_{DS}=12.5\text{V}, I_D=20\text{A}$		15.3	19	nC
$Q_g(4.5\text{V})$	Total Gate Charge			7.4	9	nC
$Q_{gs}$	Gate Source Charge			2.7		nC
$Q_{gd}$	Gate Drain Charge			4.3		nC
$t_{D(\text{on})}$	Turn-On Delay Time	$V_{GS}=10\text{V}, V_{DS}=12.5\text{V}, R_L=0.625\Omega, R_{\text{GEN}}=3\Omega$		8		ns
$t_r$	Turn-On Rise Time			11.7		ns
$t_{D(\text{off})}$	Turn-Off Delay Time			30		ns
$t_f$	Turn-Off Fall Time			11		ns
$t_{rr}$	Body Diode Reverse Recovery Time	$I_F=20\text{A}, dI/dt=100\text{A}/\mu\text{s}$		23.5	30	ns
$Q_{rr}$	Body Diode Reverse Recovery Charge	$I_F=20\text{A}, dI/dt=100\text{A}/\mu\text{s}$		12.8		nC

A: The value of  $R_{\text{JJA}}$  is measured with the device in a still air environment with  $T_A=25^\circ\text{C}$ .

B. The power dissipation  $P_D$  is based on  $T_{J(\text{MAX})}=175^\circ\text{C}$ , using junction-to-case thermal resistance, and is more useful in setting the upper dissipation limit for cases where additional heatsinking is used.

C: Repetitive rating, pulse width limited by junction temperature  $T_{J(\text{MAX})}=175^\circ\text{C}$ .

D. The  $R_{\text{JJA}}$  is the sum of the thermal impedance from junction to case  $R_{\text{JJC}}$  and case to ambient.

E. The static characteristics in Figures 1 to 6 are obtained using  $<300\ \mu\text{s}$  pulses, duty cycle 0.5% max.

F. These curves are based on the junction-to-case thermal impedance which is measured with the device mounted to a large heatsink, assuming a maximum junction temperature of  $T_{J(\text{MAX})}=175^\circ\text{C}$ .

G. The maximum current rating is limited by bond-wires.

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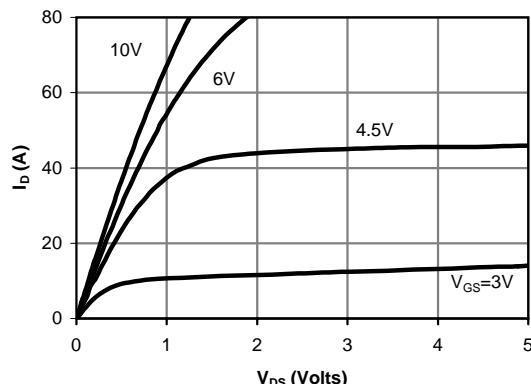
**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

Fig 1: On-Region Characteristics

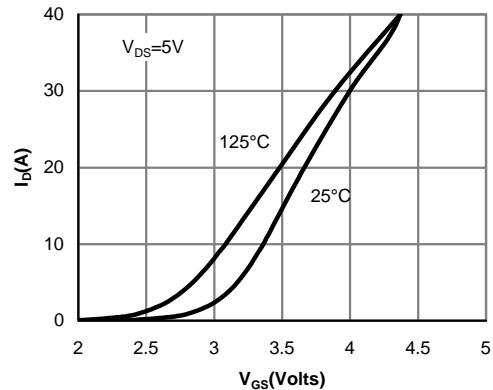


Figure 2: Transfer Characteristics

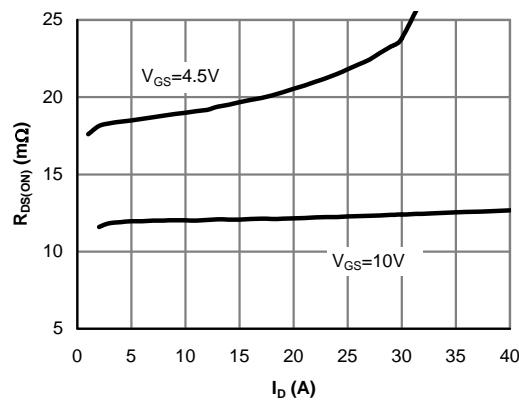


Figure 3: On-Resistance vs. Drain Current and Gate Voltage

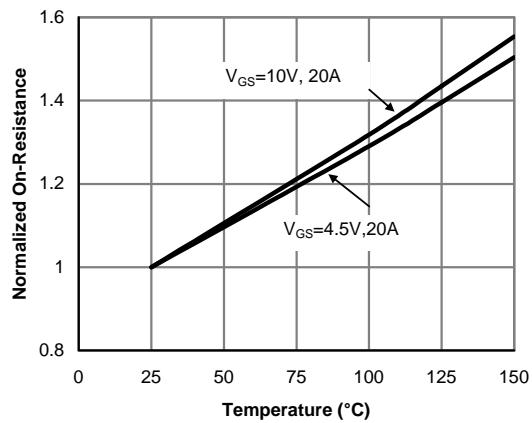


Figure 4: On-Resistance vs. Junction Temperature

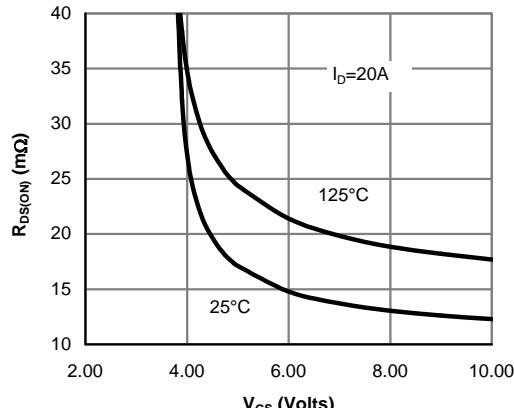


Figure 5: On-Resistance vs. Gate-Source Voltage

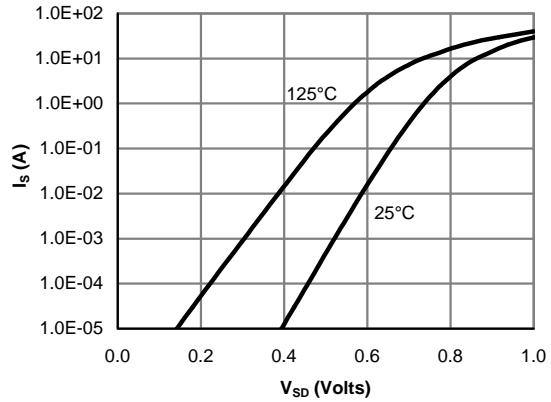


Figure 6: Body-Diode Characteristics

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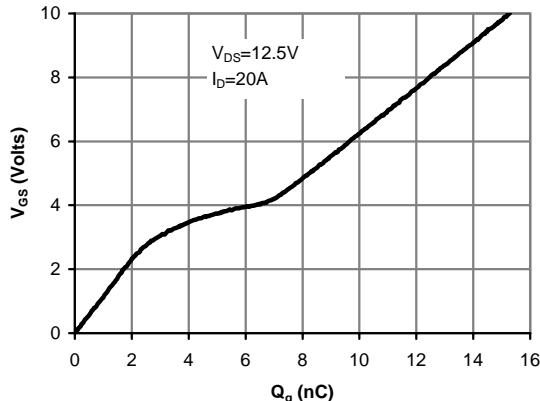


Figure 7: Gate-Charge Characteristics

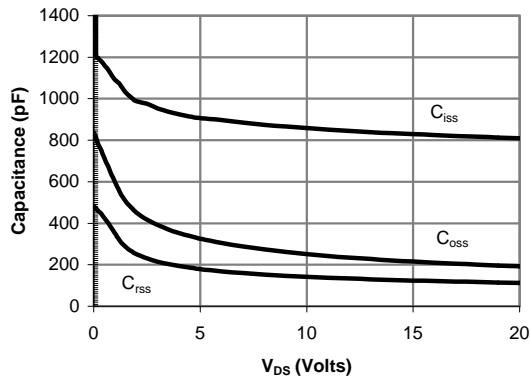


Figure 8: Capacitance Characteristics

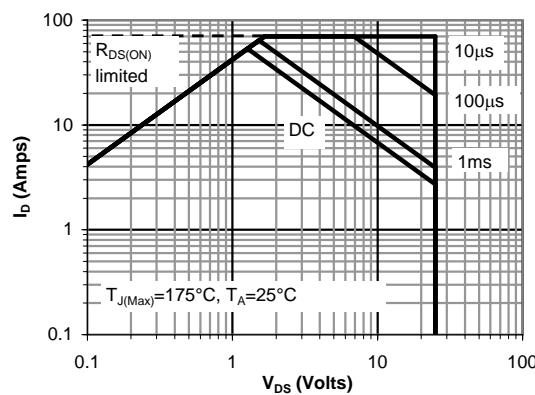


Figure 9: Maximum Forward Biased Safe Operating Area (Note E)

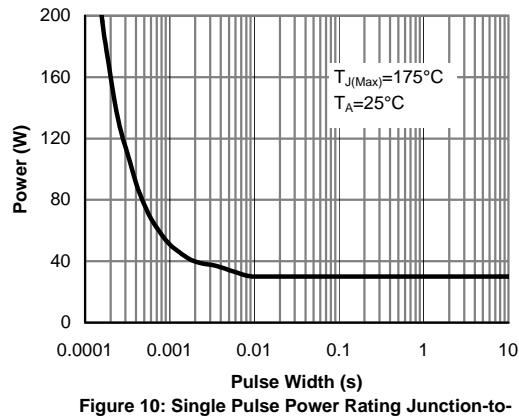


Figure 10: Single Pulse Power Rating Junction-to-Case (Note F)

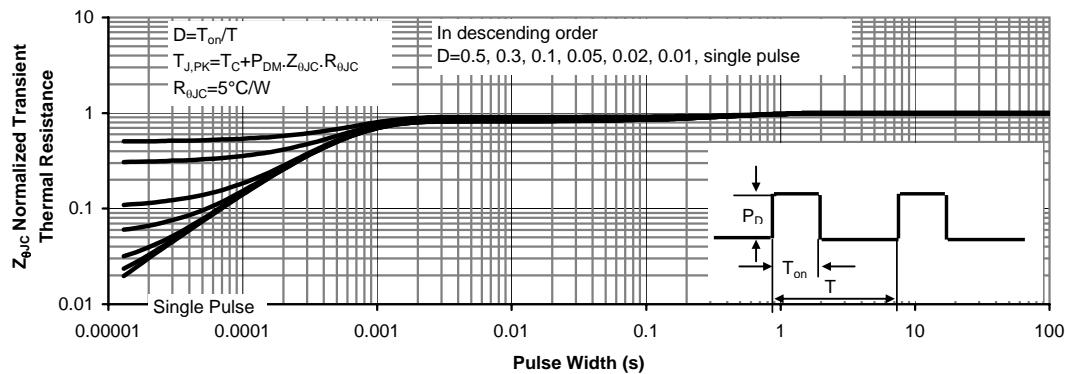


Figure 11: Normalized Maximum Transient Thermal Impedance (Note F)

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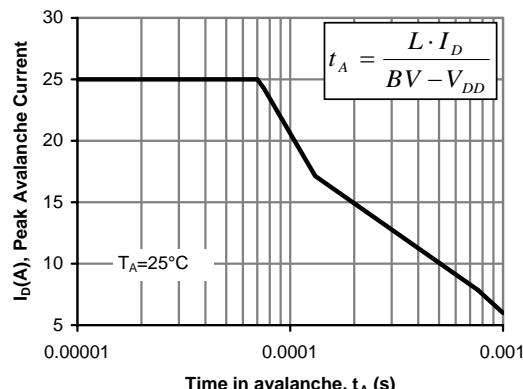
**TYPICAL ELECTRICAL AND THERMAL CHARACTERISTICS**

Figure 12: Single Pulse Avalanche capability

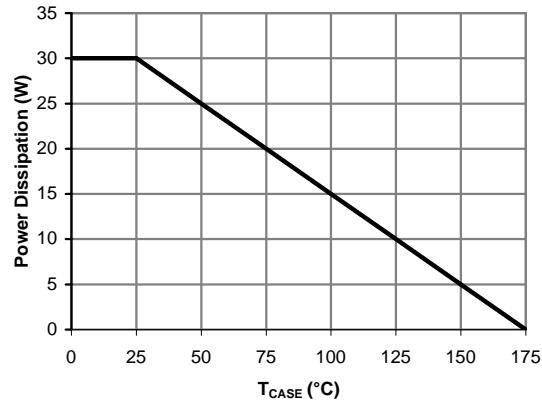


Figure 13: Power De-rating (Note B)

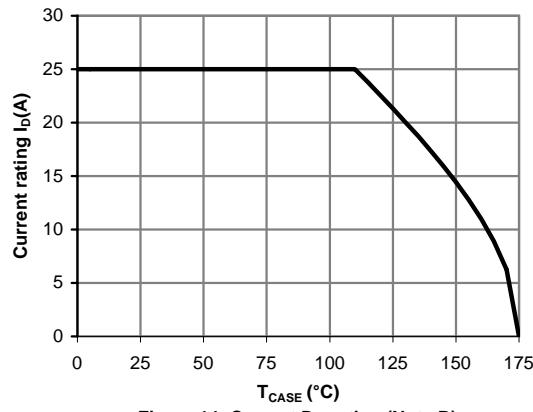


Figure 14: Current De-rating (Note B)